

Enabling cross-layer reliability and functional safety assessment through ML-based compact models

Alexandrescu, Dan; **Balakrishnan, Aneesh**; Lange, Thomas; Glorieux, Maximilien Proceedings : 2020 26th IEEE International Symposium on On-Line Testing and Robust System Design : IOLTS 2020, Napoli, Italy, July 13-16, 2020 : virtual edition 2020 / 6 p. : ill <https://doi.org/10.1109/IOLTS50870.2020.9159750>

High-level test data generation for software based self-test in microprocessors

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Teaching digital system test

Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes; Kruus, Margus The 27th EAEEIE Annual Conference : June 7-9, 2017, Grenoble 2017 / [6] p